# CERTIFICATION REPORT

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## Certified Reference Material

## BAM-L104

## TiC single layer on 100Cr6 steel

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## Abbreviations and symbols

as used within the report in alphabetical order:

| | |
|---|---|
| ABS | Arc Bond Sputtering |
| AES | Auger Electron Spectroscopy |
| AFM | Atomic Force Microscopy |
| c | phase velocity of surface acoustic waves |
| cps | counts per second |
| CRM | Certified Reference Material |
| DAP | Deutsches Akkreditierungssystem Prüfwesen GmbH |
| DIN | Deutsches Institut für Normung e.V. |
| $d_a$ | average layer thickness measured by SEM |
| $d_{SAW}$ | average layer thickness measured by SAW |
| $d_{SiO_2}$ | average layer thickness of the $SiO_2$ reference coating |
| $d_i$ | layer thickness at different points |
| $d_{CRM}$ | certified layer thickness |
| $E_{IT}$ | indentation modulus (can be correlated to Young's modulus) |
| EN | Euro-Norm |
| ESCA | Electron Spectroscopy for Chemical Analysis |
| f | frequency |
| $F_{Ar}$ | Argon flow rate |
| $F_{max}$ | maximum test force |
| $F_{C2H2}$ | acetylene flow rate |
| GD-OES | Glow Discharge Optical Emission Spectroscopy |
| GIXRD | Grazing Incidence X-Ray Diffraction |
| $H_{IT}$ | indentation hardness (can be correlated to Vickers' hardness) |
| $h_{max}$ | maximum indentation depth |
| $I_{coil}$ | magnetic coil current |
| $i_n$ | absolute intensity of reflexes |
| $I_{nx}$ | relative intensity deviation of identical reflexes with respect to the average of this reflex of all samples |
| ISO | International Organisation for Standardisation |
| P | electrical power |
| $PI_n$ | relative intensity deviation with respect to the average of the sums of normalised reflex intensities of all samples |
| PVD | Physical Vapour Deposition |
| $R_a$ | roughness average |
| $R_{max}$ | maximum roughness depth |
| $R_z$ | mean roughness depth |
| SAW | Surface Acoustic Waves |
| sccm | standard cubic centimeter per minute |
| SEM | Scanning Electron Microscopy |
| StAA | Standard Arbeitsanweisung (standard testing procedure) |
| T | temperature |
| $U_{BIAS}$ | BIAS voltage |
| UBM | Unbalanced Magnetron |

| | |
|---|---|
| $U(d_{CRM})$ | expanded uncertainty of certified layer thickness (k = 2) |
| $u(d_a)$ | standard uncertainty of average layer thickness |
| $u_c(d_{CRM})$ | combined standard uncertainty of certified layer thickness |
| $u(d_{SiO_2})$ | standard uncertainty of layer thickness measurements for ideal samples |
| $u(d_{SEM})$ | standard uncertainty of layer thickness measured by SEM |
| $u(d_{SAW})$ | standard uncertainty of layer thickness within deposition levels measured by SAW |
| WLI | White Light Interferometry |
| $\Delta_{corr}$ | correction of layer thickness measured for ideal samples by SEM |

## 1. Scope

This report describes the certification of the layer thickness of TiC coatings that are useful for the evaluation and calibration of depth measurement and depth resolution of surface analytical methods (e.g. GD-OES, AES, ESCA) and for the evaluation and calibration of metallographic preparation methods (e.g. cross-sectioning, ball-grinding).

TiC coatings with a nominal layer thickness of 2.5 µm have been deposited on polished 100Cr6 steel substrates (discs of 30 mm in diameter and 4 mm thickness) using a PVD UBM sputtering process. To improve adhesion, a Cr inter-layer with a layer thickness of approximately 100 nm was used.

For each CRM, a value of the averaged layer thickness $d_{CRM}$ is certified with respect to deposition levels. The certified value $d_{CRM}$ is valid for the central surface area of a diameter of 25 mm. The determination of the certified value was performed by means of a validated and calibrated scanning electron microscope (SEM) at cross-sections of batch reference samples.

The certification procedure was conducted in a laboratory of BAM accredited according to DIN EN ISO/IEC 17025 [1] (DAP-PL-2614.08). Wherever possible, BAM reference procedures [2] have been used.

## 2. Design and preparation

### 2.1 Substrate-related features

100Cr6 steel substrates (discs of 30 mm in diameter and 4 mm thickness) have been polished to a mirror finish ($R_a$ = 0.03 µm; $R_z$ = 0.2 µm according to DIN EN ISO 4287/4288 [3]) using metallographic standard procedures. The substrate material contains (besides iron) the following elements (weight %), [4]: C: 0.90-1.05 %; Si: 0.15-0.25 %; Mn: 0.25-0.45 %; Cr: 1.35-1.65 %; Cu < 0.3 %; Ni < 0.3 %).

### 2.2 Coating-related features

TiC coatings with Cr inter-layer have been prepared by means of PVD UBM sputtering in a commercial deposition system HTC 625 Multilab ABS™ (HAUSER Techno Coating) similar to that described in detail elsewhere [5].

Sputter targets were made from solid Ti- (99.99% purity) and Cr-plates (99.95% purity). Ar

(99.999% purity) and $C_2H_2$ (99.999% purity) were used as working and reactive gases.

To avoid any influence of sample clamps on the homogeneity of the coatings, the substrates were mounted on special substrate holders (Fig. 1). These holders are fixed on a planetary rotational system (Fig. 2) which can rotate around two axes. The frequency of rotation around the first axis was 10 rev/min.

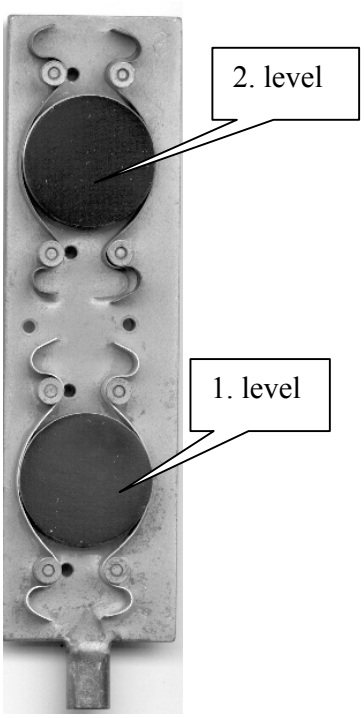



**Fig. 1:** Lower substrate holder with clamps and mounting levels 1 and 2

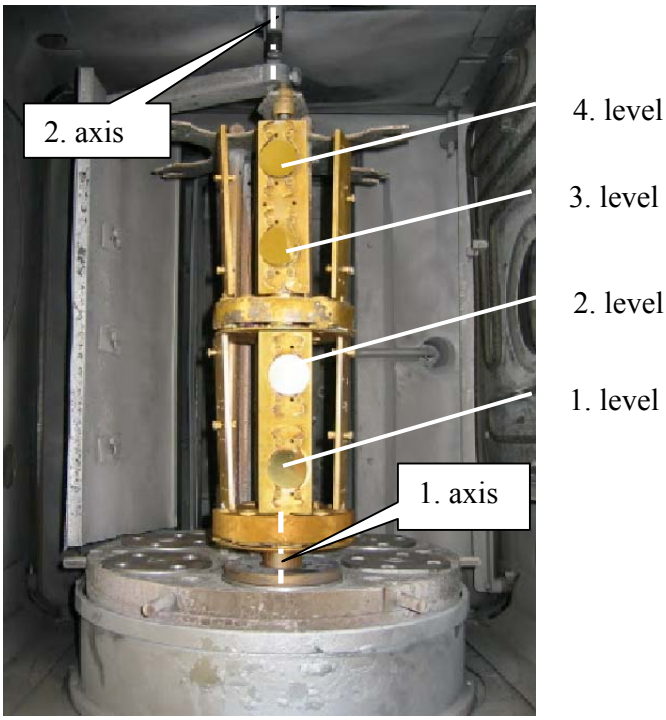



**Fig. 2:** Planetary rotational system with one pair of upper and lower substrate holders

By rotation around the second axis, the sample holders move automatically in fixed positions in front of the Cr-target for Cr deposition or the T-target for TiC deposition. Argon flow rate ($F_{Ar}$ =150 sccm), acetylene flow rate ($F_{C2H2}$=24 sccm), source power (P = 3 kW), bias voltage (100 V), coil current (3 A) and temperature (T = 380°C) were kept constant for the TiC deposition period (t=9000 sec).

In this case, and as proved for this set-up, deposition rate and corresponding layer thickness depend only on the mounting level of the substrates in the deposition chamber. In case of carbides, there is a gradient in the flow rate of acetylene in the deposition chamber. Due to

this fact, the samples of the different mounting levels may also have slightly a different chemical compositions.

Three sets of samples (deposition batches 509, 513, 515) have been prepared, using four mounting levels for substrates (Fig. 2). An example of a complete deposition sequence is provided in the appendix.

Each set of samples includes 16 reference materials (L104/#) for non-destructive testing by SAW and GIXRD and 4 batch reference samples (BL104/#) for additional destructive testing (cross-sections) and SEM inspection. Prior to cross-sectioning, batch reference samples (BL104/#) have been additionally coated with a Cr coating using PVD UBM sputtering.

The position of all individual samples on different mounting levels is given in Table 1.

**Table 1:** Sample positions and mounting levels

batch 509

| | | | | | |
|---|---|---|---|---|---|
| 4. level | L104/025 | L104/028 | L104/029 | L104/031 | BL104/629 |
| 3. level | L104/024 | L10400/26 | L104/022 | L104/030 | BL104/628 |
| 2. level | L104/003 | L104/006 | L104/015 | L104/027 | BL104/631 |
| 1. level | L104/001 | L104/004 | L104/009 | L104/023 | BL104/630 |

batch 513

| | | | | | |
|---|---|---|---|---|---|
| 4. level | L104/041 | L104/043 | L1040/45 | L104/047 | BL104/636 |
| 3. level | L104/040 | L104/042 | L104/044 | L104/046 | BL104/634 |
| 2. level | L104/033 | L104/035 | L104/037 | L104/039 | BL104/637 |
| 1. level | L104/032 | L104/034 | L104/036 | L104/038 | BL104/632 |

batch 515

| | | | | | |
|---|---|---|---|---|---|
| 4. level | L104/057 | L104/059 | L104/061 | L104/063 | BL104/480 |
| 3. level | L104/056 | L104/058 | L104/060 | L104/062 | BL104/459 |
| 2. level | L104/049 | L104/051 | L104/053 | L104/055 | BL104/635 |
| 1. level | L104/048 | L104/050 | L104/052 | L104/054 | BL104/633 |

## 3. Certification

### 3.1 Strategy of certification

The average layer thickness $d_a$ was measured according to StAA-No. VIII.23-5 [6] and StAA-No. VIII.23-PM [7] at cross-sections using a calibrated SEM. The certification strategy was as follows:

1. For all batch reference samples, destructive testing has been performed. Preparation method (cross-sectioning) and measurement method (SEM) have been validated using reference $SiO_2$ coatings on Silicon. Prior to destructive testing, the layer thickness of $SiO_2$ coatings has been determined non-destructively and independently by spectroscopic ellipsometry (SE), BAM reference procedure [2], according to StAA-Nr. VIII.2901-V.2.01 [8]. Further details are given in sec. 3.2 and in the certification report BAM-L101.
2. The average layer thickness $d_a$ of TiC was calculated from measurements at 5 points along the cross-section of the batch reference samples using validated and calibrated preparation and measurement methods described before.
3. As shown for BAM-L102 (TiN), SAW data are sensitively correlated to the mounting level of samples in the deposition chamber. As a result of this evaluation, for VN, VC and TiC non-destructive testing by means of SAW was restricted on samples of the mounting levels with the lowest respectively highest deposition rate. So, a fingerprint of layer thickness, Young's modulus, Poisson's ratio and density was taken.
4. The average layer thickness $d_a$ determined for the batch reference samples of each mounting level was identified as the certified value of layer thickness $d_{CRM}$ for samples of identical mounting levels.

### 3.2 Validation of the certification method

The preparation method (cross-sectioning) and the measurement method (SEM) have been additionally validated and re-calibrated using $SiO_2$ reference coatings on Silicon. An example of a cross-section of a $SiO_2$ reference coating on Si, coated with a TiN hard top coating, is shown in Fig. 3.

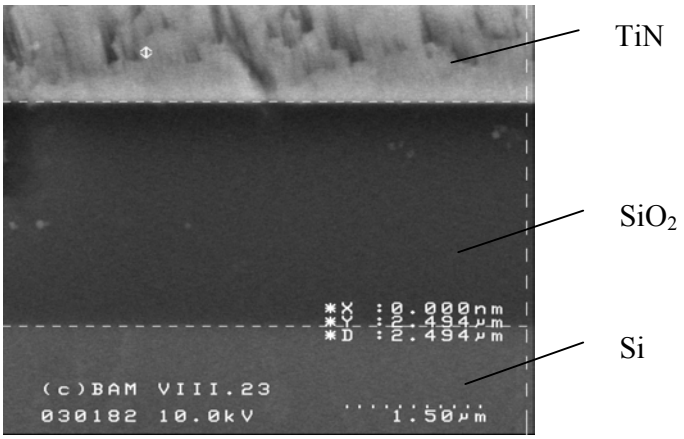



**Fig.3:** Cross-section of a $SiO_2$ reference coating on Si with TiN hard top coating

Table 2 provides 12 measurements of the layer thickness of $SiO_2$ at different points along the cross-section. The evaluation length was 5 µm for each measurement.

**Table 2:** Thickness of cross-sections of $SiO_2$ reference coatings (coated with TiN) on Si

| **measurement - ID** | **d/µm** |
|---|---|
| 30170 | 2.57 |
| 30172 | 2.45 |
| 30173 | 2.47 |
| 30174 | 2.45 |
| 30175 | 2.47 |
| 30177 | 2.47 |
| 30178 | 2.46 |
| 30179 | 2.46 |
| 30180 | 2.44 |
| 30181 | 2.54 |
| 30182 | 2.49 |
| 30183 | 2.48 |
| average value | 2.48 |
| standard uncertainty $u(d_{SiO_2})$ | 0.05 |

The average layer thickness $d_{SiO_2}$ of $SiO_2$ reference coating was derived to

$$d_{SEM,SiO_2} = (2.48 \pm 0.05)\ \mu\text{m}. \qquad (1)$$

For the validation of the preparation method (cross-sectioning) and the certification method (SEM), this result was compared with the layer thickness of $SiO_2$ derived from SE using the BAM reference procedure [2] spectroscopic ellipsometry according to StAA-No. VIII.2901-V.2.01 [8]. From the analysis of ellipsometric data, the average layer thickness of the $SiO_2$ reference coating was derived to

$$d_{SE,SiO_2} = (2.51 \pm 0.01)\ \mu\text{m}. \qquad (2)$$

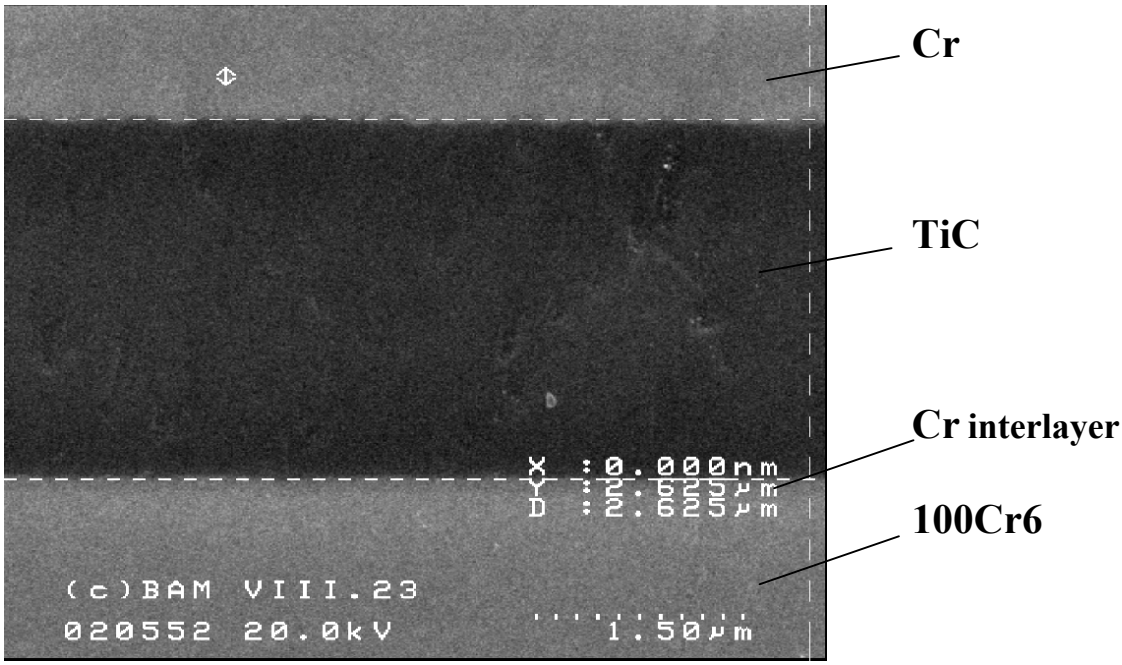
For the calculation of the certified layer thickness of TiC, the difference $(d_{SEM,SiO_2} - d_{SE,SiO_2})$ was taken as a constant correction ($\Delta_{corr}$ = 0.03 µm) for the TiC layer thickness measured by SEM .

### 3.3 Certification measurements

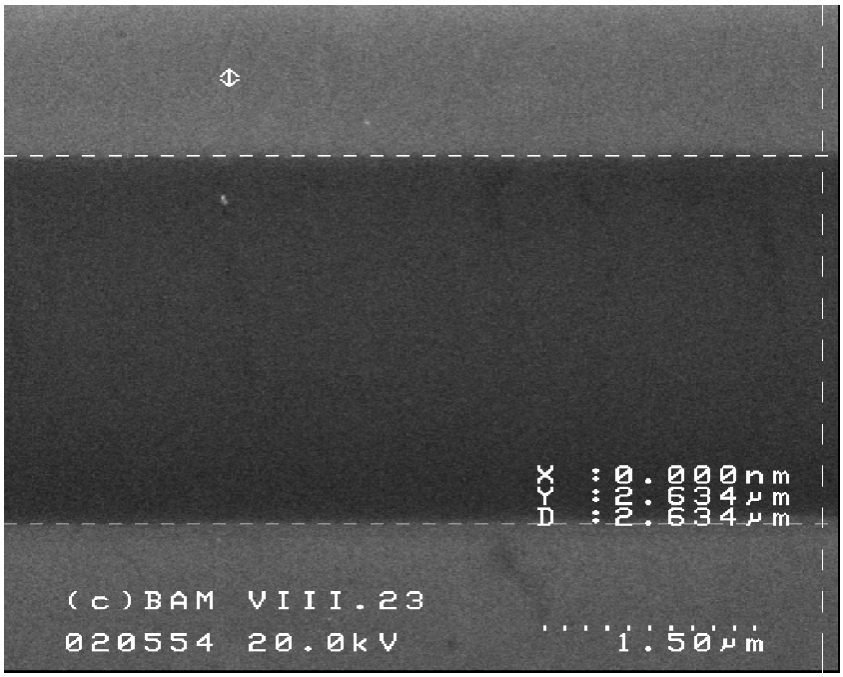
#### 3.3.1 Average layer thickness of batch reference samples

As a result of the standard calibration procedure of the SEM, it was shown that the uncertainty of the length measurements $u(d_{SEM})$ is 10 nm for ideal samples. As an example, for the measurement of layer thickness by SEM, a cross-section of a TiC batch reference sample (coated with a Cr top coating) is shown in Figs. 4 a-b. The average layer thickness $d_a$ and the standard uncertainty $u(d_a)$ were calculated from measurements at 5 different points ($d_{1-5}$) along the cross-section.

**Fig.4:** Measurement of the layer thickness of a TiC batch reference sample (coated with a Cr top coating)




a) 1. measurement of layer thickness BL104/632: $d_1$ = 2.63 µm




b) 2. measurement of layer thickness BL104/632: $d_2$ = 2.63 µm

### 3.3.2 Evaluation of batch homogeneity

The batch homogeneity in terms of a 100% testing of all samples of all four-mounting levels has been evaluated non-destructively for Ti/Al (BAM-L100) and TiN (BAM-L102) by means of grazing incidence X ray diffraction (GIXRD) and surface acoustic waves (SAW) [9, 10]. It was shown that the standard uncertainty of the layer thickness within one deposition level is approximately 3%.

For TiC reference materials, all samples of mounting levels with the lowest and highest deposition rate have been tested non-destructively by means of surface acoustic waves (SAW).

For coated materials, the phase velocity of surface acoustic waves depends on the elastic parameters and the density of both the coating and substrate material and the layer thickness [11]. Since the penetration depth of the surface acoustic wave decreases with increasing frequency, the higher frequency range is primarily influenced by the coating whereas the lower frequency range is dominated by the substrate. This results in a dispersion of phase velocity c(f) of the surface acoustic wave. A laser-acoustic technique measures the dispersion of phase velocity as a function of frequency (experimental dispersion curve). By means of a parameterised model (theoretical dispersion curve), the modulus of the coating is derived by fitting the theoretical on the experimental dispersion curve.

Fig. 5 shows the dispersion curves for reference samples of mounting level with the highest deposition rate (batch 513, 2.level) and calculated dispersion curves for a TiC layer with different thickness within the bandwidth of 20 MHz to 60 MHz.

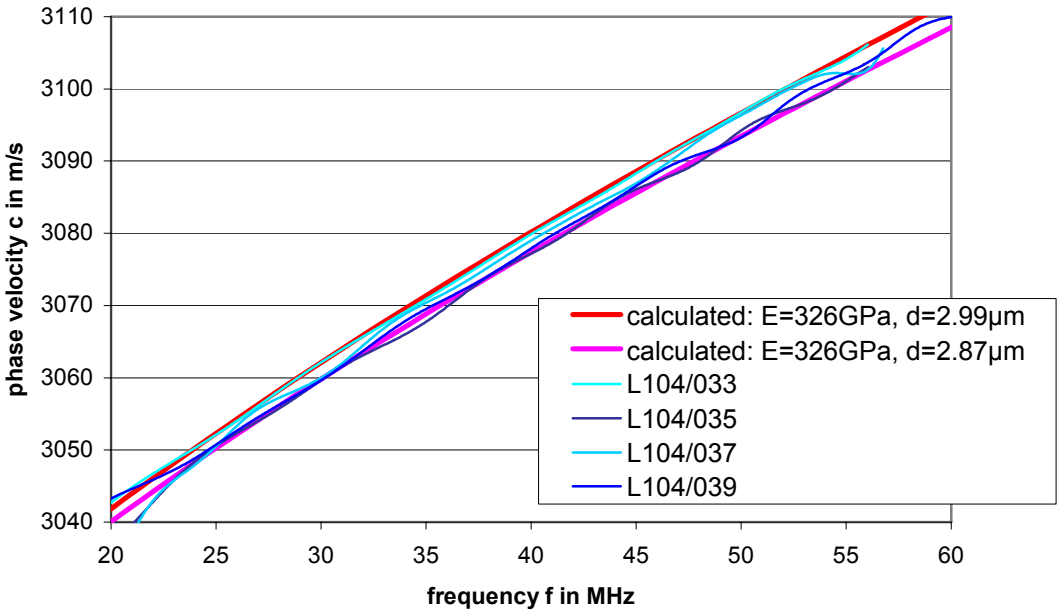



**Fig.5**: Dispersion curves for TiC reference samples (batch 513, mounting level 2)

Young's modulus $E_{SAW}$ and the average layer thickness $d_{SAW}$ of the two different levels, deduced by fitting the theoretical dispersion curve [11] on the experimental one within the bandwidth of 20 MHz to 60 MHz, are given in Table 3.

**Table 3**: Evaluation of the reproducibility of overall coating quality

| batch / level | $d_a + \Delta_{corr}$ / µm | $E_{SAW}$/ GPa | average value of $d_{SAW}$ / µm | $u(d_{SAW})$ / µm |
|---|---|---|---|---|
| 513 / 4 | 2.41 | 231 | 2.34 | 0.113 |
| 513 / 2 | 2.91 | 326 | 2.92 | 0.056 |

As shown (Table 3), TiC layers of levels 2 (maximum deposition rate) and 4 (minimum deposition rate) have different Young's modules ($E_{SAW}$) as result of slightly different chemical composition.

The model parameters for the fit are summarised in Table 4.

**Table 4**: SAW model parameters

| | Young's modulus/ GPa | Poisson's ratio | density g/cm³ |
|---|---|---|---|
| TiC coating | | 0.200 | 5.00 |
| 100Cr6 steel | 210 | 0.293 | 7.80 |
| Cr coating | 270 | 0.210 | 7.19 |

### 3.4 Summary of certification results

1. The standard calibration procedure of the SEM Hitachi S4100 (BAM StAA-No. VIII.23-PM1) results in an uncertainty of length measurements of $u(d_{SEM}) = 10$ nm.
2. The additional evaluation of the certification method SEM by means of SE as a standard-free reference method results in a constant correction $\Delta_{corr} = +30$ nm.
3. From cross-sections of the batch reference samples, the average layer thickness $d_a$ and the standard uncertainty $u(d_a)$ have been derived by SEM.
4. The average layer thickness $d_a$ with the standard uncertainty $u(d_a)$ of batch reference samples has been identified as the certified layer thickness for reference samples of the same mounting level.
5. The upper bound of the standard uncertainty of the layer thickness within mounting level with the highest deposition rate measured by SAW was taken as constant $u(d_{SAW}) = 0.06$ µm (Table 3).
6. Consequently, the certified value for the layer thickness can be written as follows:

$$d_{CRM} = d_a + \Delta_{corr} \qquad (3)$$

$$u_c(d_{CRM}) = \sqrt{[u(d_a)]^2 + [u(d_{SiO_2})]^2 + [u(d_{SEM})]^2 + [u(d_{SAW})]^2} \qquad (4)$$

$$U(d_{CRM}) = k * u_c(d_{CRM}), \qquad (k = 2) \qquad (5)$$

All certification results are summarised in Table 5.

**Table 5:** Certification results

| sample ID | batch | level | $d_{CRM}$ / µm | $U(d_{CRM})$ / µm, k=2 |
|---|---|---|---|---|
| L104/001 | B509 | 1 | 2.70 | 0.18 |
| L104/003 | B509 | 2 | 2.99 | 0.16 |
| L104/004 | B509 | 1 | 2.70 | 0.18 |
| L104/006 | B509 | 2 | 2.99 | 0.16 |
| L104/009 | B509 | 1 | 2.70 | 0.18 |
| L104/015 | B509 | 2 | 2.99 | 0.16 |
| L104/022 | B509 | 3 | 2.83 | 0.16 |
| L104/023 | B509 | 1 | 2.70 | 0.18 |
| L104/024 | B509 | 3 | 2.83 | 0.16 |

| | | | | |
|---|---|---|---|---|
| L104/025 | B509 | 4 | 2.44 | 0.19 |
| L104/026 | B509 | 3 | 2.83 | 0.16 |
| L104/027 | B509 | 2 | 2.99 | 0.16 |
| L104/028 | B509 | 4 | 2.44 | 0.19 |
| L104/029 | B509 | 4 | 2.44 | 0.19 |
| L104/030 | B509 | 3 | 2.83 | 0.16 |
| L104/031 | B509 | 4 | 2.44 | 0.19 |
| L104/032 | B513 | 1 | 2.66 | 0.16 |
| L104/033 | B513 | 2 | 2.91 | 0.16 |
| L104/034 | B513 | 1 | 2.66 | 0.16 |
| L104/035 | B513 | 2 | 2.91 | 0.16 |
| L104/036 | B513 | 1 | 2.66 | 0.16 |
| L104/037 | B513 | 2 | 2.91 | 0.16 |
| L104/038 | B513 | 1 | 2.66 | 0.16 |
| L104/039 | B513 | 2 | 2.91 | 0.16 |
| L104/040 | B513 | 3 | 2.79 | 0.16 |
| L104/041 | B513 | 4 | 2.41 | 0.17 |
| L104/042 | B513 | 3 | 2.79 | 0.16 |
| L104/043 | B513 | 4 | 2.41 | 0.17 |
| L104/044 | B513 | 3 | 2.79 | 0.16 |
| L104/045 | B513 | 4 | 2.41 | 0.17 |
| L104/046 | B513 | 3 | 2.79 | 0.16 |
| L104/047 | B513 | 4 | 2.41 | 0.17 |
| L104/048 | B515 | 1 | 2.57 | 0.17 |
| L104/049 | B515 | 2 | 2.83 | 0.21 |
| L104/050 | B515 | 1 | 2.57 | 0.17 |
| L104/051 | B515 | 2 | 2.83 | 0.21 |
| L104/052 | B515 | 1 | 2.57 | 0.17 |
| L104/053 | B515 | 2 | 2.83 | 0.21 |
| L104/054 | B515 | 1 | 2.57 | 0.17 |
| L104/055 | B515 | 2 | 2.83 | 0.21 |
| L104/056 | B515 | 3 | 2.79 | 0.16 |
| L104/057 | B515 | 4 | 2.41 | 0.16 |
| L104/058 | B515 | 3 | 2.79 | 0.16 |
| L104/059 | B515 | 4 | 2.41 | 0.16 |
| L104/060 | B515 | 3 | 2.79 | 0.16 |
| L104/061 | B515 | 4 | 2.41 | 0.16 |
| L104/062 | B515 | 3 | 2.79 | 0.16 |
| L104/063 | B515 | 4 | 2.41 | 0.16 |

## 4. Stability testing

The stability of the reference material has been evaluated by repeated GIXRD measurements after 400 days. Samples have been stored under ordinary laboratory conditions. One example of these measurements is shown in Fig. 6.

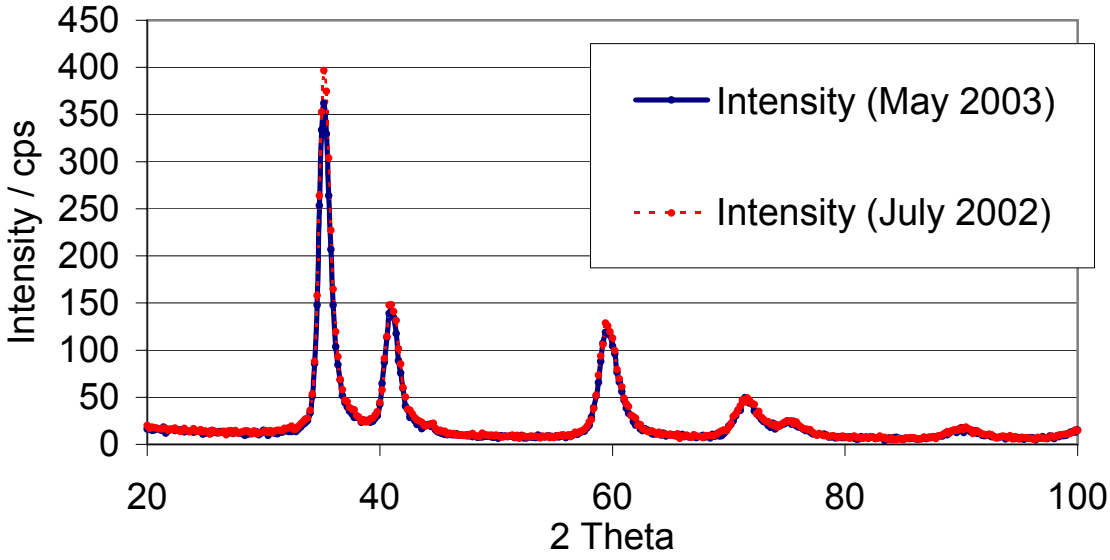



**Fig.6:** Repeated GIXRD measurements after 400 days of storage (sample L104/050)

From the agreement of both measurements, i. e. no significant difference in the derived GIXRD ratios, it was concluded that the samples are stable under ordinary laboratory conditions.

## 5. Instruction for use

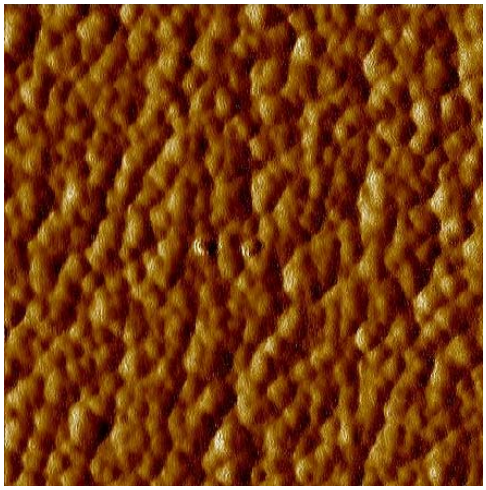
For each CRM, a value of the TiC layer thickness, valid for the central surface area of a diameter of 25 mm, was certified. In case of use, it is a prerequisite to avoid any mechanical (such as scratching) or chemical treatment (such as aggressive agents) of the surface. Storage under ordinary laboratory conditions results in an unavoidable native oxide film of some nanometer film thickness.

## 6. Additional information

### 6.1 Topography and roughness

The evaluation of roughness according to DIN EN ISO 4288 [3] with a mechanical profilometer has shown that there is no measurable difference in surface roughness between the coated and uncoated samples ($R_a$ = 0.03 µm; $R_z$ = 0.2 µm).

Moreover, the topography of the CRM was investigated by AFM for the characterisation of smaller surface areas (evaluation area was (5 x 5) µm$^2$). An example is given in Fig. 7.



$R_a$ = 10 nm

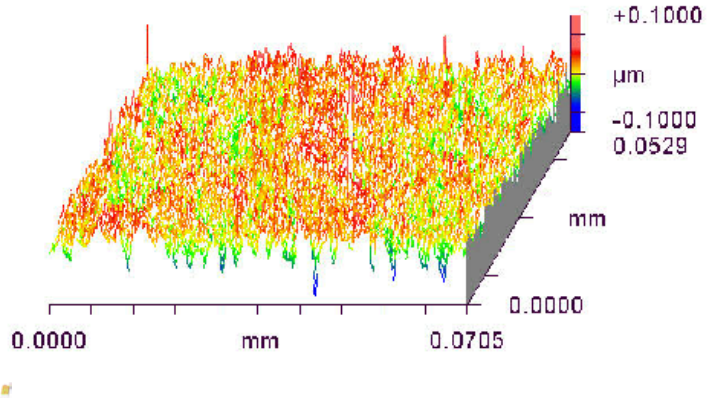
$R_{max}$ = 94 nm

$R_z$ = 82 nm

area : (5 x 5) µm²

**Fig. 7:** AFM-topography (BAM-L104/056)

In addition, WLI (evaluation area was (70 x 50) µm$^2$) has been used for the characterisation of larger surface areas. An example is shown in Fig. 8. Table 6 summarises the results of WLI measurements.




$R_a$= 0.02 µm

$R_{max}$ = 0.78 µm

$R_z$ = 0.36 µm

area : (70 x 70) µm²

**Fig. 8:** WLI-topography (BAM-L104/056)

**Table 6:** Summary of the WLI – measurements

| **no.** | **sample ID** | **batch / level** | **$R_z$ / µm** |
|---|---|---|---|
| 1 | L104/022 | 509/3 | 0.55 |
| 2 | L104/038 | 512/1 | 1.96 |
| 3 | L104/039 | 513/2 | 1.03 |
| 4 | L104/040 | 513/3 | 1.93 |
| 5 | L104/041 | 513/4 | 1.93 |
| 6 | L104/056 | 515/3 | 0.36 |
| | | **average value** | 1.29 |
| | | **standard deviation** | 0.74 |

### 6.2 Mechanical properties

Mechanical properties ($H_{IT}$, $E_{IT}$) of BAM-L104/050 were determined by instrumented indentation tests ($F_{max}$ = 10 mN, $h_{max}$ = 156 nm, 100 indentations averaged over an area of (20 x 20) $mm^2$) according to DIN EN ISO 14577 [12] and StAA VIII.2901-V.1.11 [13] as follows:

$H_{IT}$ = (30 ± 8) GPa

$E_{IT}$ = (334 ± 72) GPa

### 6.3 Microstructure

Microstructure and texture of TiC coating have been evaluated for each reference material and all batch reference samples by means of grazing incidence X-ray diffraction (GIXRD). A typical GIXRD diagram is shown in Fig.6.

As described in more detail earlier [14], normalised intensity ratios were calculated for evaluation of the reproducibility of overall coating quality (Table 7).

**Table 7:** GIXRD-intensity ratios (batch 513)

| level | sample ID | $PI_n$ TiC | $i_n$ TiC (35.9.7°) | $i_n$ TiC (41.7°) | $i_n$ TiC (60.5°) | $i_n$ TiC (73.4°) |
|---|---|---|---|---|---|---|
| 1 | L 104/032 | 1.04 | 485.4 | 138.8 | 146.5 | 50.2 |
| 2 | L 104/033 | 0.88 | 469.8 | 104.3 | 126.9 | 46.1 |
| 3 | L 104/040 | 0.99 | 524.2 | 126.4 | 142.9 | 47.8 |
| 4 | L 104/041 | 1.26 | 511.1 | 190.6 | 163.7 | 56.4 |
| 1 | L 104/034 | 0.97 | 475.0 | 130.4 | 135.6 | 46.6 |
| 2 | L 104/035 | 0.88 | 474.8 | 101.3 | 127.3 | 46.4 |
| 3 | L 104/042 | 0.97 | 522.0 | 107.7 | 150.2 | 49.7 |
| 4 | L 104/043 | 1.17 | 470.1 | 183.2 | 151.4 | 51.4 |
| 1 | L 104/036 | 0.94 | 433.9 | 133.5 | 124.2 | 44.8 |
| 2 | L 104/037 | 0.84 | 413.9 | 110.1 | 114.2 | 42.4 |
| 3 | L 104/044 | 0.95 | 483.7 | 119.3 | 137.7 | 46.8 |
| 4 | L 104/045 | 1.12 | 464.3 | 176.1 | 143.8 | 49.5 |
| 1 | L 104/038 | 1.01 | 434.9 | 146.2 | 132.9 | 46.8 |
| 2 | L 104/039 | 0.85 | 429.5 | 109.0 | 117.1 | 42.8 |
| 3 | L 104/046 | 0.95 | 530.4 | 102.1 | 151.6 | 48.3 |
| 4 | L 104/047 | 1.17 | 509.7 | 178.7 | 152.3 | 52.8 |

A Seifert X-ray diffractometer XRD 3000 TT was used for GIXRD measurements. Each sample was analysed at an angle of incidence of 2° to the surface with sample rotation. The evaluation area was 1.5 cm². From the absolute intensity of reflexes ($i_n$ in cps), the relative intensity deviation $I_{nx}$ of identical reflexes was calculated with respect to the average of this reflex of all samples (equation 6), and the relative intensity deviation $PI_n$ was calculated with respect to the average of the sums of normalised reflex intensities of all samples (equation 7). The data for each sample of batch 513 are given in Table 7.

$$I_{nx} = \frac{i_{nx} n}{\sum_{n} i_{nx}} \qquad (6)$$

$$PI_{n} = \frac{\sum_{x} I_{nx} n}{\sum_{n} \sum_{x} I_{nx}} \qquad (7)$$

The relative intensity deviations $PI_n$ for each sample are shown in Fig. 9 in dependence on the mounting level for batch 513.

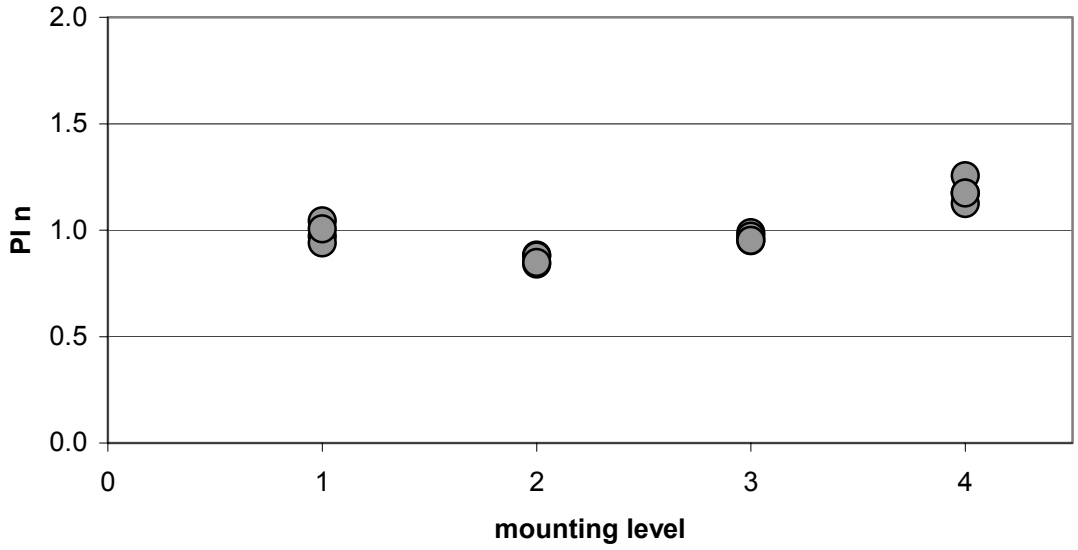



**Fig. 9:** Relative intensity deviations $PI_n$ in dependence on the mounting level (batch 513)

## 7. References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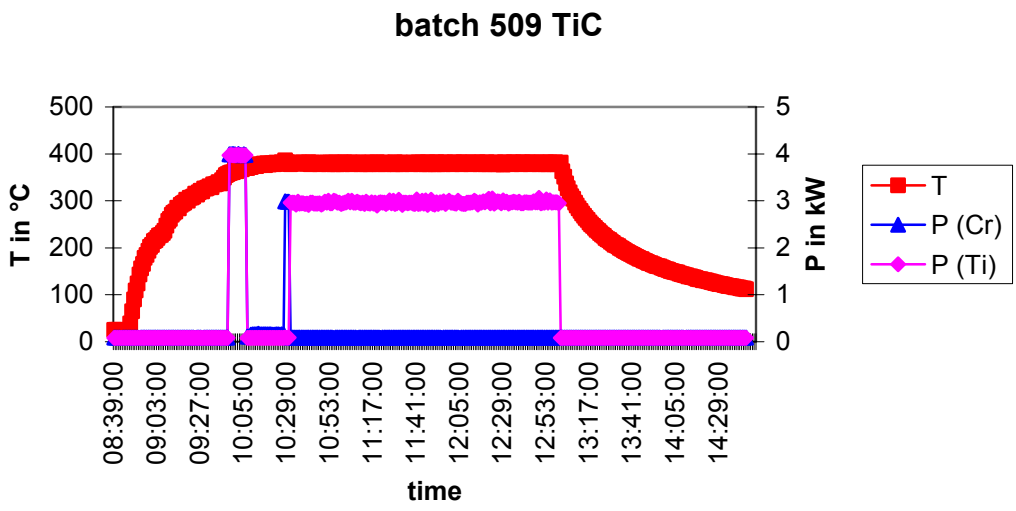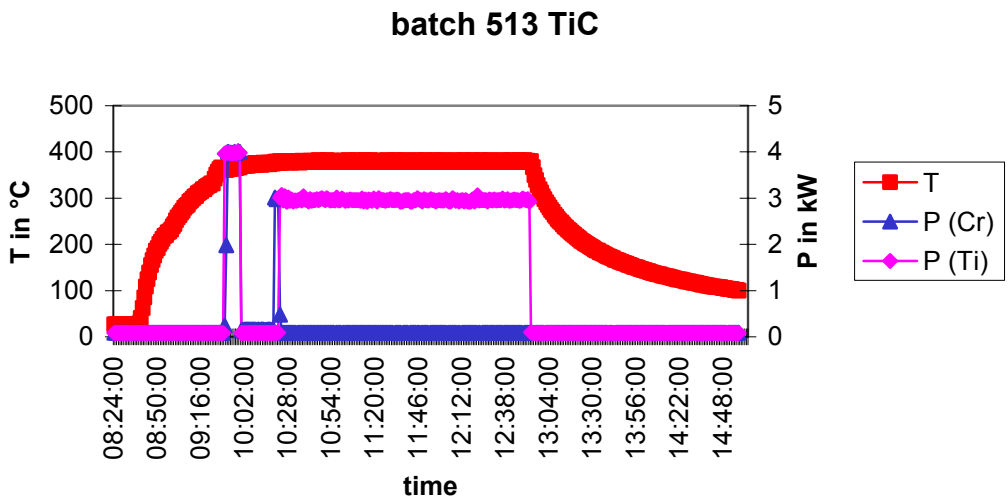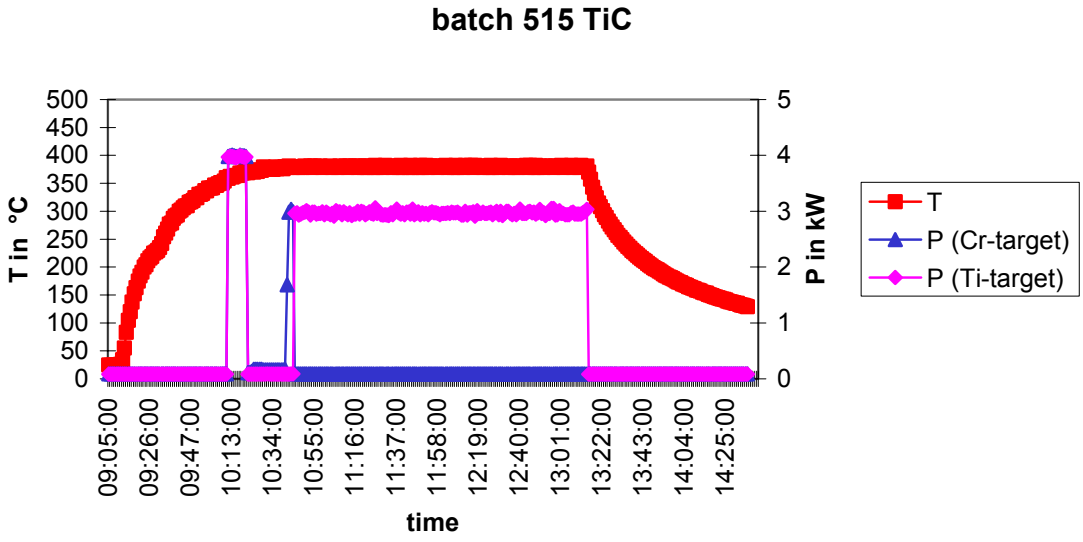
**Appendix:** Information on preparation